Freeform Search

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Term:	Documents in <u>Display Format</u> : - Starting with Number 1	Database:	US OCR Full-Text Database EPO Abstracts Database JPO Abstracts Database Derwent World Patents Index	
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DB=PGI	PB, USPT, EPAB, JPAB, DWPI, TDBD; PLUR = Y	ES; OP=OR	
<u>L9</u>	15 and L8	7	<u>L9</u>
<u>L8</u>	16 near3 L7	8	<u>L8</u>
<u>L7</u>	memory adj bank	13773	<u>L7</u>
<u>L6</u>	isr or (interrupt adj service adj routine)	7199	<u>L6</u>
<u>L5</u>	(12 or 13) with L4	233	<u>L5</u>
<u>L4</u>	interrupt	249085	<u>L4</u>
<u>L3</u>	bank near3 (switch\$ or select\$)	20966	<u>L3</u>
<u>L2</u>	page near2 select\$	21604	<u>L2</u>
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<u>#3</u>	((interrupt service routine) <in>metadata)</in>	13
<u>#4</u>	((((interrupt service routine) <in>metadata))<and> (bank<in>metadata))</in></and></in>	0



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